BANGLADESH UNIVERSITY OF ENGINEERING AND TECHNOLOGY DEPARTMENT OF ELECTRICAL AND ELECTRONIC ENGINEERING



EEE 468 (January 2024)

VLSI Laboratory

Final Project Report

Section: G1 Group: 01

12-bit Rotator

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1 Objectives:

The goals of our project are:

- ❖ To understand how RTL code works.
- Understand several testbench methods.
- ❖ To get familiar with the concepts of coverage.
- Synthesis of the proposed design in Cadence.
- ❖ To get familiar with physical design and PnR process.

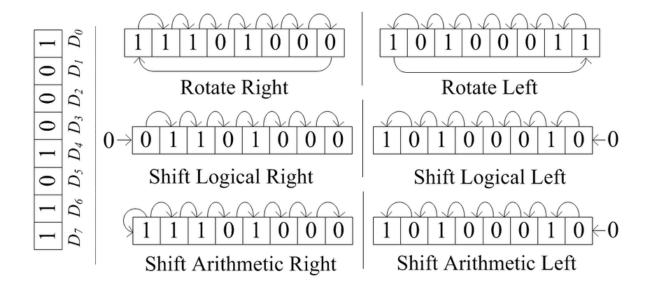
2 Design Steps:

We followed the four following steps:

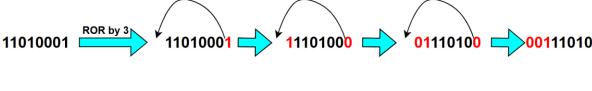
- ❖ Developing the design code and directed testbench with waveforms.
- Implementing layered testbench with maximum coverage.
- Doing the optimized synthesis process.
- ❖ Doing the optimized PnR process with maximized chip density with respect to die area, pin planning and power rails.

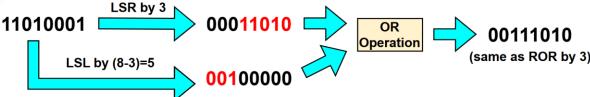
3 Theory:

The rotating operation works as follows:



In order to perform ROR (Rotate Right) and ROL (Rotate left) operation with LSR (Shift Logical Right) and LSL (shift Logical Left), we can follow the following process:





Same explanation goes for ROL. So, if we use a 12-bit number and rotation(i.e-right) has to be done for it, at first, we need to perform LSR by the given amount of rotation and then we need to perform LSL by 12 minus rotation amount and finally by doing OR operation we can have the desired result. As the rotate amount is defined as 4-bit, any number between 0 to 15 can be used. On the other hand, the input is defined as 12-bit. So, a reduced rotate amount variable can be defined using modulo operation by 12 for faster operation.

4 Step-1 (Design Code & Directed Testbench):

Design code for 12-bit rotator:

4.1 design.sv

```
module bit rotator(
    input wire [11:0] Din,
    input wire [3:0] Ramt,
    input wire L, // Direction: 0 = right rotate, 1 = left rotate
    output reg [11:0] Dout
);
 wire [3:0]Ramt_reduced;
  assign Ramt_reduced = Ramt%12;
    always @(*) begin
        if (L == 1) begin
            // Left rotate
            Dout = (Din << Ramt_reduced) | (Din >> (12 - Ramt_reduced));
        end else begin
            // Right rotate
            Dout = (Din >> Ramt_reduced) | (Din << (12 - Ramt_reduced));</pre>
        end
    end
```

endmodule

The directed testbench with waveforms for our design code is given below:

4.2 testbench.sv:

```
module testbench;
    reg [11:0] Din;
    reg [3:0] Ramt;
    reg L;
    wire [11:0] Dout;
    bit rotator uut (
        .Din(Din),
        .Ramt(Ramt),
        .L(L),
        .Dout(Dout)
    );
    initial begin
      $dumpfile("dumpfile.vcd");
        $dumpvars;
        Din = 12'b101010101010;
        Ramt = 4'd0:
        L = 0;
        #10;
        $display("Test 1 - No rotation (Right): Din = %b, Dout = %b", Din, Dout);
        Din = 12'b101010101010;
        Ramt = 4'd0;
        L = 1;
        #10;
        $display("Test 2 - No rotation (Left): Din = %b, Dout = %b", Din, Dout);
        Din = 12'b101010101010;
        Ramt = 4'd12;
        L = 0;
        #10;
        $display("Test 3 - Full rotation (Right): Din = %b, Dout = %b", Din,
Dout);
        Din = 12'b101010101010;
        Ramt = 4'd12;
        L = 1;
        #10;
        $display("Test 4 - Full rotation (Left): Din = %b, Dout = %b", Din,
Dout);
        Din = 12'b101010101010;
        Ramt = 4'd1;
        L = 0;
        $display("Test 5 - Right rotation by 1: Din = %b, Dout = %b", Din, Dout);
        Din = 12'b101010101010;
        Ramt = 4'd1;
        L = 1;
        #10;
        $display("Test 6 - Left rotation by 1: Din = %b, Dout = %b", Din, Dout);
```

```
Din = 12'b110011001100;
        Ramt = 4'd11;
        L = 0;
        #10:
        $display("Test 7 - Right rotation by 11: Din = %b, Dout = %b", Din,
Dout);
        Din = 12'b110011001100;
        Ramt = 4'd11:
        L = 1;
        #10:
        $display("Test 8 - Left rotation by 11: Din = %b, Dout = %b", Din, Dout);
        Din = 12'b111100001111;
        Ramt = 4'd6;
        L = 0;
        #10;
        $display("Test 9 - Right rotation by 6: Din = %b, Dout = %b", Din, Dout);
        Din = 12'b111100001111;
        Ramt = 4'd6;
        L = 1;
        $display("Test 10 - Left rotation by 6: Din = %b, Dout = %b", Din, Dout);
        $finish;
    end
endmodule
```

4.3 Result:

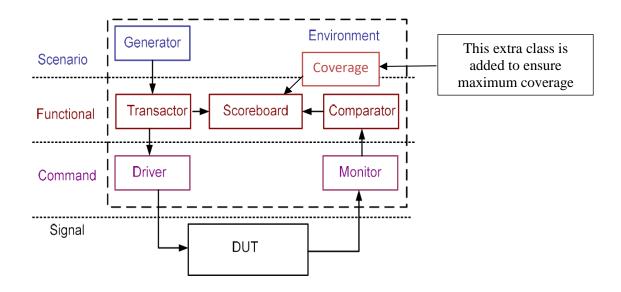
Here, 10 test cases are successfully verified. It can also be verified by the waveforms.

4.4 Waveforms:



The waveforms also verify the testcases. For example, for Ramt=h'11, we will get h'999 for right rotation and h'666 for left rotation which are justified from the waveforms.

5 Step-2 (Layered Testbench with Maximized Coverage):



The necessary .sv files are given according to the schematic:

5.1 environment.sv:

```
include "generator.sv"
include "driver.sv"
include "monitor.sv"
include "scoreboard.sv"

class environment;
  mailbox gen2driv;
  mailbox driv2sb;
  mailbox mon2sb;

generator gen;
  driver drv;
  monitor mon;
```

```
scoreboard scb;
 event driven;
 virtual rot_if rotif;
 function new(virtual rot_if rotif);
   this.rotif=rotif;
    gen2driv=new();
    driv2sb=new();
    mon2sb=new();
    gen=new(gen2driv);
    drv=new(gen2driv,driv2sb,rotif.DRIVER,driven);
    mon=new(mon2sb,rotif.MONITOR,driven);
    scb=new(driv2sb,mon2sb);
 endfunction
 task main(input int count);
    fork gen.main(count);
          drv.main(count);
          mon.main(count);
          scb.main(count);
    join
    $finish;
 endtask:main
 function int get_pass_count();
    return scb.pass_count;
  endfunction
 function int get_fail_count();
    return scb.fail_count;
 endfunction
endclass
```

5.2 interface.sv:

```
interface rot_if(input clk);

logic [11:0] Din;
logic [3:0] Ramt;
logic L;
logic [11:0] Dout;

clocking driver_cb @(negedge clk);
  default input #1 output #1;
  output Din, Ramt, L;
endclocking

clocking mon_cb @(negedge clk);
  default input #1 output #1;
  input Din, Ramt, L;
  input Dout;
endclocking

modport DRIVER (clocking driver cb, input clk);
```

```
modport MONITOR (clocking mon_cb, input clk);
endinterface
```

5.3 generator.sv:

```
`include "transaction.sv"
class generator;
 mailbox gen2driv;
 transaction g trans, custom trans;
 function new(mailbox gen2driv);
    this.gen2driv=gen2driv;
 endfunction
 task main(input int count);
    repeat(count) begin
     g_trans=new();
      g_trans=new custom_trans;
      assert(g_trans.randomize());
      gen2driv.put(g_trans);
    end
  endtask:main
endclass:generator
```

5.4 transaction.sv:

```
class transaction;
  rand bit [11:0] Din;
  rand bit [3:0] Ramt;
  //rand bit S;
  rand bit L;
 bit [11:0] Dout;
endclass:transaction
```

5.5 driver.sv:

```
class driver;
 mailbox gen2driv, driv2sb;
 virtual rot_if.DRIVER rotif;
 transaction d trans;
 event driven;
 function new(mailbox gen2driv, driv2sb , virtual rot_if.DRIVER rotif, event
driven);
   this.gen2driv=gen2driv;
    this.rotif=rotif;
   this.driven=driven;
    this.driv2sb=driv2sb;
 endfunction
```

```
task main(input int count);
    repeat(count) begin
      d_trans=new();
      gen2driv.get(d_trans);
      @(rotif.driver_cb);
      rotif.driver cb.Din <= d trans.Din;</pre>
      rotif.driver cb.Ramt <= d trans.Ramt;</pre>
         rotif.driver cb.L <= d trans.L;</pre>
      driv2sb.put(d_trans);
      -> driven;
    end
  endtask:main
endclass:driver
```

5.6 monitor.sv:

```
class monitor;
 mailbox mon2sb;
 virtual rot if.MONITOR rotif;
 transaction m_trans;
 event driven;
 function new(mailbox mon2sb, virtual rot_if.MONITOR rotif, event driven);
    this.mon2sb=mon2sb;
    this.rotif=rotif;
    this.driven=driven;
 endfunction
 task main(input int count);
    @(driven);
    @(rotif.mon cb);
    repeat(count) begin
      m_trans=new();
      @(posedge rotif.clk);
      m trans.Dout=rotif.mon cb.Dout;
      //m trans.Cout=counterif.mon cb.Cout;
      mon2sb.put(m trans);
    end
  endtask:main
```

5.7 coverage.sv:

endclass:monitor

```
class rot_coverage;
  // Variables to sample
 bit [11:0] Din, Dout;
 bit L;
 bit [3:0] Ramt;
```

```
covergroup cg;
    //option.per_instance = 1;
    //option.comment = "Rot coverage";
    // Cover basic input values
    Din_cp: coverpoint Din {
     bins min_edge = {12'h000};
     bins max_edge = {12'hFFF};
     bins others[4] = {[12'h001:12'hFFE]}; // Split other values into 4 bins
    L_cp: coverpoint L;
    Ramt cp: coverpoint Ramt;
    // Cross coverage
    LDin_cross: cross L_cp, Din_cp {
     option.weight = 2; // Important to verify Load with different A values
 endgroup
 function new();
    cg = new;
    cg.start(); // Explicitly start coverage collection
 endfunction
 function void sample(transaction trans);
   this.Din = trans.Din;
   this.Dout = trans.Dout;
   this.L = trans.L;
   this.Ramt = trans.Ramt;
    cg.sample();
 endfunction
endclass
```

5.8 scoreboard.sv:

```
include "coverage.sv"

class scoreboard;
  mailbox driv2sb;
  mailbox mon2sb;

  transaction d_trans;
  transaction m_trans;

  event driven;

  int pass_count, fail_count;
  bit test_result; // 1 for pass, 0 for fail

  // Add state tracking
  bit [11:0] expected_count;
  rot_coverage coverage;

  function new(mailbox driv2sb, mon2sb);
```

```
this.driv2sb = driv2sb;
   this.mon2sb = mon2sb;
   this.pass count = 0;
   this.fail_count = 0;
   this.expected_count = 0; // Initialize counter
   coverage = new();
                             // Initialize coverage
 endfunction
 task main(input int count);
   $display("-----");
   repeat(count) begin
     d_trans = new();
     m trans = new();
     // Get both transactions
     driv2sb.get(d trans);
     mon2sb.get(m_trans);
     // Calculate expected value based on inputs
     if(d_trans.L == 1)
     expected_count = (d_trans.Din << ((d_trans.Ramt)%12)) | (d_trans.Din >> (12)
- ((d trans.Ramt)%12)));
   else
     expected count = (d trans.Din >> ((d trans.Ramt)%12)) | (d trans.Din << (12
- ((d_trans.Ramt)%12)));
     // Compare with actual value
     test_result = (m_trans.Dout == expected_count);
     // Sample coverage after each transaction
     coverage.sample(d_trans);
     if(test result) begin
       pass_count++;
       $display("||Passed||Din = %b || Ramt = %d || L = %d || Expected_out = %b
|| Resulted_out =
%b",d trans.Din,d trans.Ramt,d trans.L,expected count,m trans.Dout );
     end else begin
       fail count++;
       $display("||Failed||Din = %b || Ramt = %d || L = %d || Expected_out = %b
|| Resulted out =
%b",d trans.Din,d trans.Ramt,d trans.L,expected count,m trans.Dout );
     end
   end
   $display("-----");
   $display("Total Passes: %0d, Total Fails: %0d", pass_count, fail_count);
   $display("-----");
   $display("Coverage: %.2f%", coverage.cg.get_coverage());
 endtask
endclass
```

5.9 testcases.sv:

```
`include "environment.sv"
program test(input int count, rot if rotif, output int pass count, output int
```

```
fail_count, output bit test_done);
 environment env;
 class testcase01 extends transaction;
    constraint c_A {
     Din dist {
       12'h000 :/ 20,
       12'hFFF :/ 20,
        [12'h001:12'hFFE] :/ 60
     };
    constraint c_edge {
      Ramt inside {[0:15]};
      L inside {[0:1]};
 endclass
 initial begin
   testcase01 testcase01handle;
   testcase01handle = new();
    env = new(rotif);
    env.gen.custom_trans = testcase01handle;
    env.main(count);
    pass_count = env.get_pass_count();
    fail_count = env.get_fail_count();
    test_done = 1'b1;
 end
endprogram:test
```

5.10 testbench.sv:

```
`include "testcases.sv"
`include "interface.sv"
module testbench;
 bit clk;
  int pass_count, fail_count;
 bit test_done;
 always #5 clk = \simclk;
  int count = 31; // Increased test count for better coverage
 rot if rotif(clk);
 test test01(count, rotif, pass_count, fail_count, test_done);
  initial begin
    $dumpfile("dump.vcd");
    $dumpvars;
  end
 bit_rotator DUT (
    .Din(rotif.Din),
```

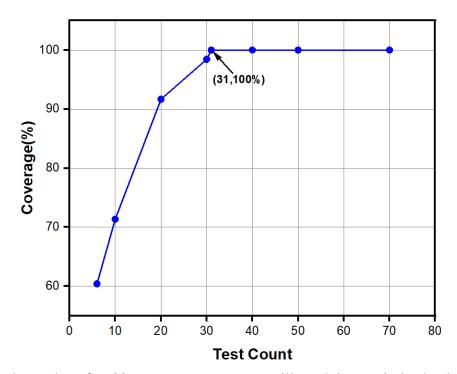
```
.Ramt(rotif.Ramt),
.L(rotif.L),
.Dout(rotif.Dout)
);
initial begin
  #4;
end
endmodule
```

5.11 Result:

```
------Scoreboard Test Starts-----
||Passed||Din = 000000000000 || Ramt = 8 || L = 0 || Expected_out = 00000000000 || Resulted_out = 000000000000
||Passed||Din = 11111111111 || Ramt = 5 || L = 0 || Expected_out = 111111111111 || Resulted_out = 11111111111
||Passed||Din = 110101101110 || Ramt = 1 || L = 0 || Expected_out = 011010110111 || Resulted_out = 011010110111
||Passed||Din = 111111111111 || Ramt = 2 || L = 1 || Expected_out = 111111111111 || Resulted_out = 11111111111
||Passed||Din = 000000000000 || Ramt = 5 || L = 1 || Expected_out = 00000000000 || Resulted_out = 000000000000
||Passed||Din = 001101100001 || Ramt = 1 || L = 0 || Expected_out = 100110110000 || Resulted_out = 100110110000
||Passed||Din = 110001000011 || Ramt = 10 || L = 0 || Expected_out = 000100001111 || Resulted_out = 000100001111
||Passed||Din = 010011101000 || Ramt = 8 || L = 1 || Expected_out = 100001001110 || Resulted_out = 100001001110
||Passed||Din = 000000000000 || Ramt = 15 || L = 1 || Expected_out = 00000000000 || Resulted_out = 000000000000
||Passed||Din = 000000000000 || Ramt = 9 || L = 0 || Expected_out = 00000000000 || Resulted_out = 000000000000
||Passed||Din = 000000000000 || Ramt = 4 || L = 1 || Expected_out = 00000000000 || Resulted_out = 000000000000
||Passed||Din = 000110010011 || Ramt = 9 || L = 0 || Expected_out = 110010011000 || Resulted_out = 110010011000
||Passed||Din = 010111111010 || Ramt = 6 || L = 0 || Expected_out = 111010010111 || Resulted_out = 111010010111
||Passed||Din = 101011000011 || Ramt = 14 || L = 1 || Expected_out = 101100001110 || Resulted_out = 101100001110
||Passed||Din = 010000011100 || Ramt = 4 || L = 0 || Expected_out = 110001000001 || Resulted_out = 110001000001
||Passed||Din = 101000000001 || Ramt = 4 || L = 0 || Expected_out = 000110100000 || Resulted_out = 000110100000
||Passed||Din = 110010010010 || Ramt = 8 || L = 0 || Expected_out = 100100101100 || Resulted_out = 100100101100
||Passed||Din = 010111011011 || Ramt = 3 || L = 0 || Expected_out = 011010111011 || Resulted_out = 011010111011
||Passed||Din = 001010000010 || Ramt = 6 || L = 1 || Expected_out = 000010001010 || Resulted_out = 000010001010
||Passed||Din = 000000000000 || Ramt = 11 || L = 1 || Expected_out = 00000000000 || Resulted_out = 000000000000
||Passed||Din = 000000001010 || Ramt = 6 || L = 1 || Expected_out = 001010000000 || Resulted_out = 001010000000
||Passed||Din = 000001100001 || Ramt = 0 || L = 1 || Expected_out = 000001100001 || Resulted_out = 000001100001
||Passed||Din = 11111111111 || Ramt = 0 || L = 0 || Expected_out = 11111111111 || Resulted_out = 11111111111
||Passed||Din = 100000100111 || Ramt = 12 || L = 0 || Expected_out = 100000100111 || Resulted_out = 100000100111
||Passed||Din = 000000100001 || Ramt = 4 || L = 0 || Expected_out = 000100000010 || Resulted_out = 000100000010
||Passed||Din = 11111111111 || Ramt = 1 || L = 0 || Expected_out = 11111111111 || Resulted_out = 11111111111
||Passed||Din = 011111101000 || Ramt = 13 || L = 1 || Expected_out = 111111010000 || Resulted_out = 111111010000
||Passed||Din = 111111111111 || Ramt = 10 || L = 0 || Expected_out = 111111111111 || Resulted_out = 111111111111
||Passed||Din = 110110000001 || Ramt = 8 || L = 1 || Expected_out = 000111011000 || Resulted_out = 000111011000
||Passed||Din = 011000010101 || Ramt = 3 || L = 1 || Expected_out = 000010101011 || Resulted_out = 00001010101
||Passed||Din = 111000100100 || Ramt = 7 || L = 0 || Expected_out = 010010011100 || Resulted_out = 010010011100
      -----Scoreboard Test Ends---
Total Passes: 31, Total Fails: 0
-----Coverage Summary------
Coverage: 100.00%
$finish called from file "environment.sv", line 39.
$finish at simulation time
```

5.12 Test Count vs Coverage(%) Plot:

Test Count	Coverage (%)
6	60.42
10	71.35
20	91.67
30	98.44
31	100
40	100
50	100
70	100



This plot shows that after 30 test counts, coverage will reach its maximized value(100%).

6 Step-3 (Synthesis with Optimized Power, Performance & Area):

Three files (bit_rotator.v, bit_rotator.tcl, bit_rotator.sdc) are required for the synthesis process.

bit_rotator.v:

```
module bit_rotator(
   input wire [11:0] Din,
   input wire [3:0] Ramt,
```

6.1 bit rotator.tcl:

```
#run Genus in Legacy UI if Genus is invoked with Common UI
::legacy::set attribute common ui false / ;
if {[file exists /proc/cpuinfo]} {
sh grep "model name" /proc/cpuinfo
sh grep "cpu MHz" /proc/cpuinfo
puts "Hostname : [info hostname]"
### Preset global variables and attributes
set DESIGN bit rotator
set SYN EFF high
set MAP_EFF high
set OPT EFF high
# Directory of PDK
#set pdk dir /home/wsadiq/buet flow/GPDK045
set pdk dir /home/cad/VLSI2Lab/Digital/library/
#set_attribute init_lib_search_path $pdk_dir/gsclib045/timing
#set attribute init hdl search path /home/wsadiq/buet flow/rtl
set attribute init lib search path $pdk dir
#set_attribute init_hdl_search_path ../../rtl
##Set synthesizing effort for each synthesis stage
set attribute syn generic effort $SYN EFF
set_attribute syn_map_effort $MAP_EFF
set attribute syn opt effort $OPT EFF
#set_attribute library "\
slow_vdd1v0_basicCells_hvt.lib \
slow_vdd1v0_basicCells.lib \
slow vdd1v0 basicCells lvt.lib"
set_attribute library "\
```

```
slow vdd1v0 basicCells.lib"
set_dont_use [get_lib_cells CLK*]
set_dont_use [get_lib_cells SDFF*]
set dont use [get lib cells DLY*]
set dont use [get lib cells HOLD*]
# If you dont want to use LVT uncomment this line
#set_dont_use [get_lib_cells *LVT*]
### Load Design
###source verilog files.tcl
read hdl "\
${DESIGN}.v"
elaborate $DESIGN
puts "Runtime & Memory after 'read_hdl'"
time info Elaboration
check design -unresolved
### Constraints Setup
read sdc bit rotator.sdc
report timing -encounter >> reports/${DESIGN} pretim.rpt
#####################
### Synthesizing to generic
syn_generic
puts "Runtime & Memory after 'syn_generic'"
time info GENERIC
report datapath > reports/${DESIGN}_datapath_generic.rpt
generate_reports -outdir reports -tag generic
write_db -to_file ${DESIGN}_generic.db
report timing -encounter >> reports/${DESIGN} generic.rpt
##This synthesizes your code
synthesize -to_mapped
## This writes all your files
write -mapped > bit_rotator_synth.v
## THESE FILES ARE NOT REQUIRED, THE SDC FILE IS A TIMING FILE
write script > script
```

6.2 bit_rotator.sdc:

```
# Setting up time units
set units -time 1ns -capacitance pF
# Setting the clock period to 10ns, as period = 1/freq, here, freq = 100MHz
set clock period 10;
# Set the top module
set top_module "bit_rotator"
# Clock port (if applicable)
set clock_port {clk}
# Reset port (if applicable)
set reset_port {rst_n}
# Setting the input ports in a list
set input_ports {Din[11:0], Ramt[3:0], L}
# Setting the output port in a list
set output_ports {Dout[11:0]}
# Define clocks
create clock -period ${clock period} -waveform {0 5} -name func clk [get ports
${clock_port}]
# Setting up constraints for the reset signal (if reset is synchronous and
multicycle)
set_multicycle_path -setup 3 -from [get_ports ${reset_port}]
set_multicycle_path -hold 2 -from [get_ports ${reset_port}]
# Define input delays (e.g., max propagation delay to input ports)
set input delay 0.4 -clock [get clocks {func clk}] ${input ports}
# Define output delays (e.g., max propagation delay from output ports)
set output delay 0.6 -clock [get clocks {func clk}] ${output ports}
```

Now, we need to optimize the synthesis process with respect to setup and hold time, clock frequency, input and output delay for different efforts (low, medium, high).

6.3 Data for Low & Medium Effort:

setup time(clock)	leakage power(nW)	internal power(nW)	net power(nW)	switching power (nW)	total area
0.1	3.62	2142.62	1039.08	3181.7	229.82
1	3.62	2142.62	1039.08	3181.7	229.82
3	3.62	2142.62	1039.08	3181.7	229.82
5	3.62	2142.62	1039.08	3181.7	229.82
8	3.62	2142.62	1039.08	3181.7	229.82

hold time(clock)	leakage power(nW)	internal power(nW)	net power(nW)	switching power (nW)	total area
0.1	3.62	2142.62	1039.08	3181.7	229.82
1	3.62	2142.62	1039.08	3181.7	229.82
2	3.62	2142.62	1039.08	3181.7	229.82
5	3.62	2142.62	1039.08	3181.7	229.82
8	3.62	2142.62	1039.08	3181.7	229.82

clock freq (MHz)	leakage power(nW)	internal power(nW)	net power(nW)	switching power (nW)	total area
20	3.62	2142.62	1039.08	3181.7	229.82
50	3.62	2142.62	1039.08	3181.7	229.82
100	3.62	2142.62	1039.08	3181.7	229.82
200	3.62	2142.62	1039.08	3181.7	229.82
500	3.62	2142.62	1039.08	3181.7	229.82
1000	3.62	2142.62	1039.08	3181.7	229.82

input delay (ns)	leakage power(nW)	internal power(nW)	net power(nW)	switching power (nW)	total area
0.1	3.62	2142.62	1039.08	3181.7	229.82
0.4	3.62	2142.62	1039.08	3181.7	229.82
0.8	3.62	2142.62	1039.08	3181.7	229.82
1.5	3.62	2142.62	1039.08	3181.7	229.82
3	3.62	2142.62	1039.08	3181.7	229.82
5	3.62	2142.62	1039.08	3181.7	229.82

output delay (ns)	leakage power(nW)	internal power(nW)	net power(nW)	switching power (nW)	total area
0.1	3.62	2142.62	1039.08	3181.7	229.82
0.3	3.62	2142.62	1039.08	3181.7	229.82
0.6	3.62	2142.62	1039.08	3181.7	229.82
2	3.62	2142.62	1039.08	3181.7	229.82
5	3.62	2142.62	1039.08	3181.7	229.82

6.4 Data for High Effort:

setup time(clock)	leakage power(nW)	internal power(nW)	net power(nW)	switching power(nW)	total area
0.1	3.61	2147.81	1038.45	3186.25	229.14
1	3.61	2147.81	1038.45	3186.25	229.14
3	3.61	2147.81	1038.45	3186.25	229.14
5	3.61	2147.81	1038.45	3186.25	229.14
8	3.61	2147.81	1038.45	3186.25	229.14

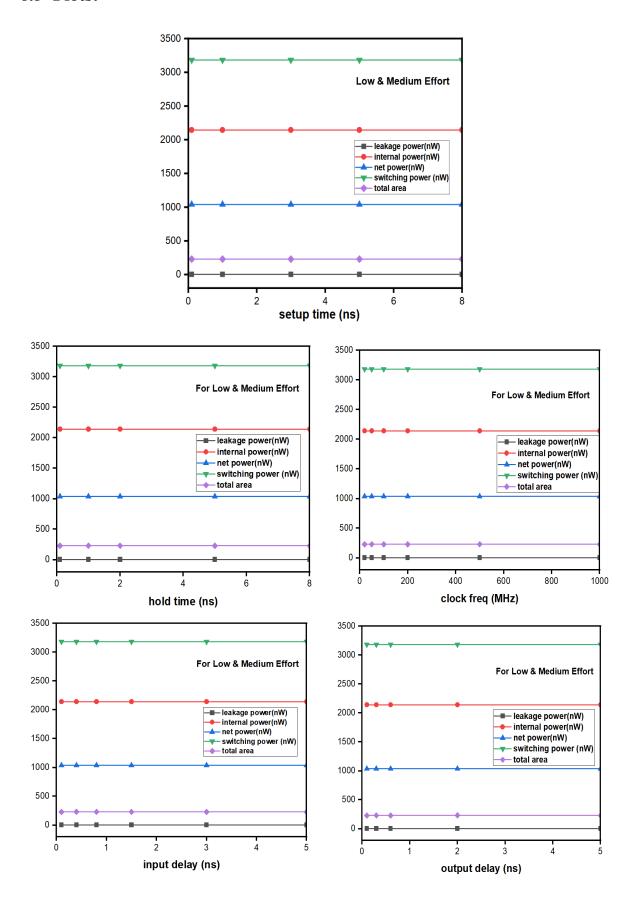
hold time(clock)	leakage power(nW)	internal power(nW)	net power(nW)	switching power(nW)	total area
0.1	3.61	2147.81	1038.45	3186.25	229.14
1	3.61	2147.81	1038.45	3186.25	229.14
2	3.61	2147.81	1038.45	3186.25	229.14
5	3.61	2147.81	1038.45	3186.25	229.14
8	3.61	2147.81	1038.45	3186.25	229.14

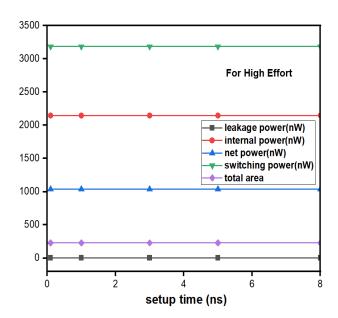
clock freq (MHz)	leakage power(nW)	internal power(nW)	net power(nW)	switching power(nW)	total area
20	3.61	2147.81	1038.45	3186.25	229.14
50	3.61	2147.81	1038.45	3186.25	229.14
100	3.61	2147.81	1038.45	3186.25	229.14
200	3.61	2147.81	1038.45	3186.25	229.14
500	3.61	2147.81	1038.45	3186.25	229.14
1000	3.61	2147.81	1038.45	3186.25	229.14

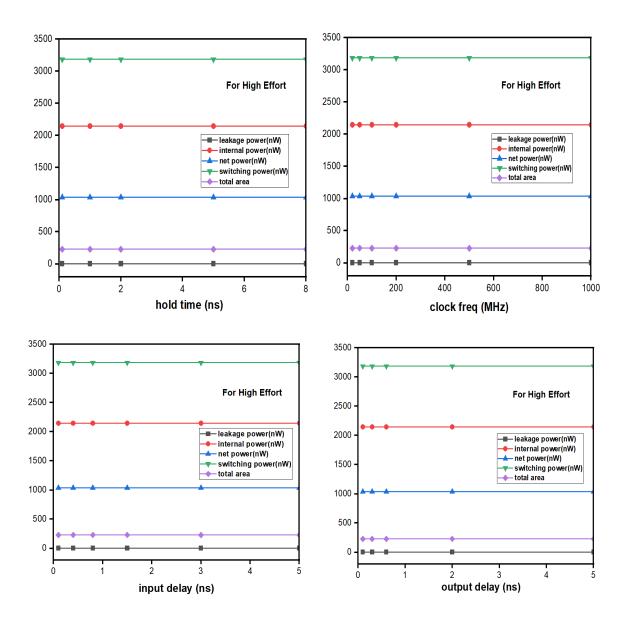
input delay (ns)	leakage power(nW)	internal power(nW)	net power(nW)	switching power(nW)	total area
0.1	3.61	2147.81	1038.45	3186.25	229.14
0.4	3.61	2147.81	1038.45	3186.25	229.14
0.8	3.61	2147.81	1038.45	3186.25	229.14
1.5	3.61	2147.81	1038.45	3186.25	229.14
3	3.61	2147.81	1038.45	3186.25	229.14
5	3.61	2147.81	1038.45	3186.25	229.14

output delay (ns)	leakage power(nW)	internal power(nW)	net power(nW)	switching power(nW)	total area
0.1	3.61	2147.81	1038.45	3186.25	229.14
0.3	3.61	2147.81	1038.45	3186.25	229.14
0.6	3.61	2147.81	1038.45	3186.25	229.14
2	3.61	2147.81	1038.45	3186.25	229.14
5	3.61	2147.81	1038.45	3186.25	229.14

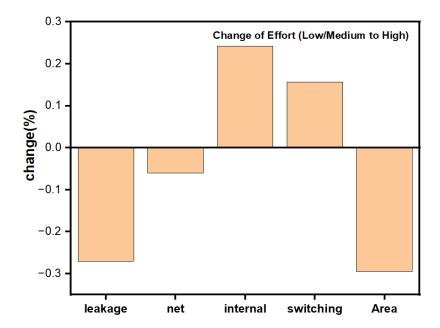
6.5 Plots:







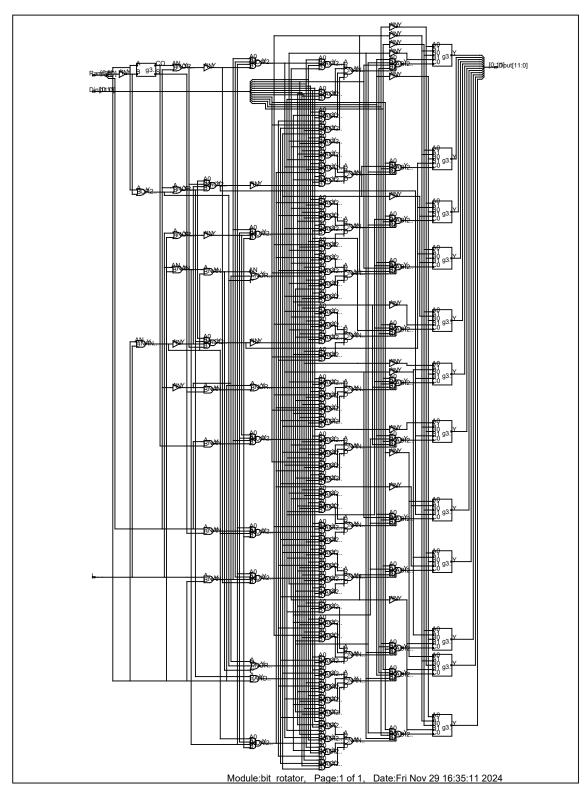
Here setup and hold time are scaled over $\frac{1}{T_{Period}}$. Here, we can observe that $P_{switch} = P_{net} + P_{internal}$. $P_{leakage}$ is independent. No change is occurring in every plot due to the absence of clock frequency. But change is observed when effort is changed from low/medium to high.



Here, we can see that in high effort, $P_{interal}$ increases and that's why P_{switch} also increases. But the other parameters (P_{leak} , P_{net} , Area) decrease in high effort. That's why we chose the high effort **bit_rotator_synth.v** for physical design.

6.6 Synthesized Design

Our Synthesized Design:



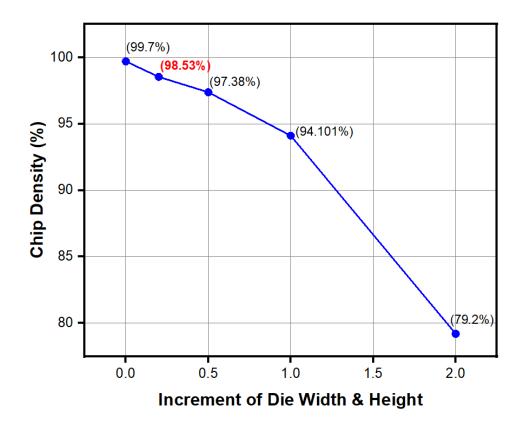
Cadence Schematics, Copyright 1997-2006

7 Step-4 (Optimized Physical Design with respect to Die Size, Pin Planning, and Power Rails):

Here we focused on maximum chip density by varying die size, pin planning and power rails. The suggested die width and height are 19.145 and 17.1. We equally incremented these values by an equal amount and listed a table.

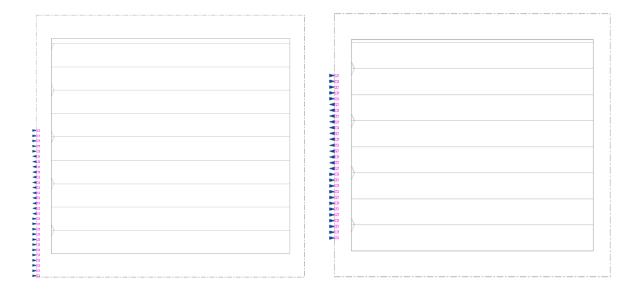
Increment Value	Die Width	Die Height
+2	21.145	19.1
+1	20.145	18.1
+0.5	19.645	17.6
+0.2	19.345	17.3
0	19.145	17.1

For this, we got the following chip density (%) vs increment value plot:

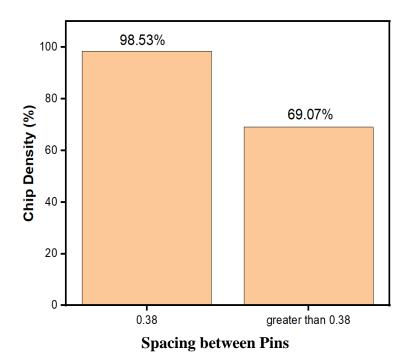


Although the maximum density is 99.7% for our design, we used the combination where we get 98.53% because the first one fails in DRC checking and all other combinations pass in DRC. For our design, we chose die width = 19.345 and die height = 17.3.

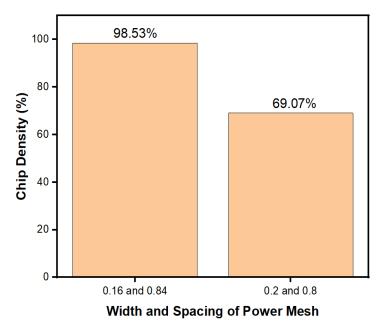
In case of pin planning position, it has no effect on chip density. For example, the following pictures of pin planning introduce zero effect on chip density.



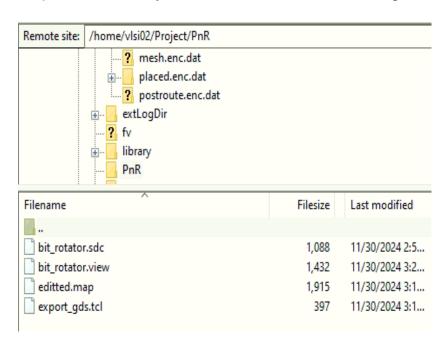
Now if spacing between the pins in the pin planning is greater than **0.38**, a value of **0.57** is auto-adjusted in the setting, and it introduces a huge drop in chip density. So, we chose **0.38** as the minimum spacing.



If the width and spacing in the power mesh are taken as **0.2** and **0.8** instead of **0.16** and **0.84** , a significant drop in chip density occurs. So, in power mesh, 0.16 and 0.84 are taken as power mesh width and spacing between them.



Now step by step processes are given with figures during the physical design. The /home/vlsi02/Project bit rotator synth.v file is in the directory. the /home/vlsi02/Project/PnR directory, these files will be used in the PnR process.



The .sdc file will be the same that we used in step-3 and editted.map file will also be same that we used in our experiment 4. Modifications are required in the bit_rotator.view and export_gds.tcl

bit_rotator.view:

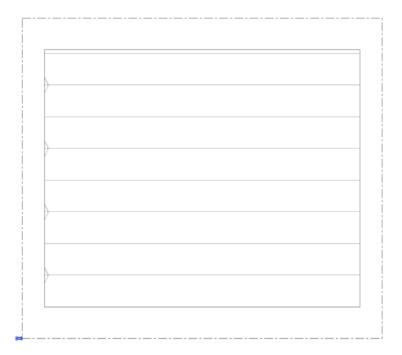
```
# Version:1.0 MMMC View Definition File
# Do Not Remove Above Line
create_rc_corner -name rcbest0 -T {0} -preRoute_res {1.0} -preRoute_cap {1.0} -
preRoute_clkres {1.0} -preRoute_clkcap {1.0} -postRoute_res {1.0} -postRoute_cap
{1.0} -postRoute xcap {1.0} -postRoute clkres {1.0} -postRoute clkcap {1.0} -
qx tech file {/home/cad/VLSI2Lab/Digital/library/gpdk045.tch}
create rc corner -name rcworst125 -T {125} -preRoute_res {1.0} -preRoute_cap
{1.0} -preRoute_clkres {1.0} -preRoute_clkcap {1.0} -postRoute_res {1.0} -
postRoute_cap {1.0} -postRoute_xcap {1.0} -postRoute_clkres {1.0} -
postRoute_clkcap {1.0} -qx_tech_file
{/home/cad/VLSI2Lab/Digital/library/gpdk045.tch}
create_library_set -name BC -timing
{/home/cad/VLSI2Lab/Digital/library/fast vdd1v0 basicCells.lib}
create_library_set -name WC -timing
{/home/cad/VLSI2Lab/Digital/library/slow_vdd1v0_basicCells.lib}
create constraint mode -name func -sdc files
{/home/vlsi02/Project/PnR/bit rotator.sdc}
create delay corner -name BC rcbest0.hold -library set {BC} -rc corner {rcbest0}
create delay corner -name WC rcworst125.setup -library set {WC} -rc corner
{rcworst125}
create analysis view -name func@BC rcbest0.hold -constraint mode {func} -
delay_corner {BC_rcbest0.hold}
create_analysis_view -name func@WC_rcworst125.setup -constraint_mode {func} -
delay_corner {WC_rcworst125.setup}
set_analysis_view -setup {func@BC_rcbest0.hold} -hold {func@BC_rcbest0.hold}
```

export_gds.tcl:

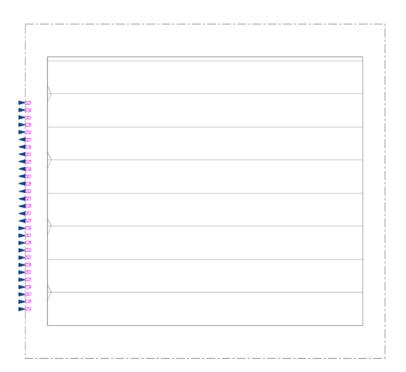
```
# Write Netlist
saveNetlist [dbGet [dbgTopCell].name].lvs_netlist.vg \
    -flat \
    -includePowerGround \
    -phys \
    -excludeLeafCell

# Write GDS
streamOut bit_rotator.merged.gds -mapFile /home/vlsi02/Project/PnR/editted.map -mode ALL -units 2000 -merge /home/cad/VLSI2Lab/Digital/library/gsclib045.gds -dieAreaAsBoundary -stripes 1 -structureName bit_rotator -libName DesignLib
```

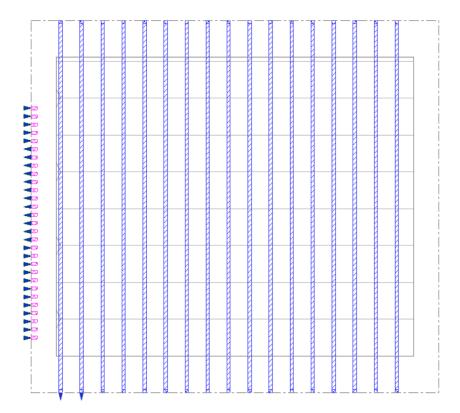
Using these, after floorplanning we got the following figure:



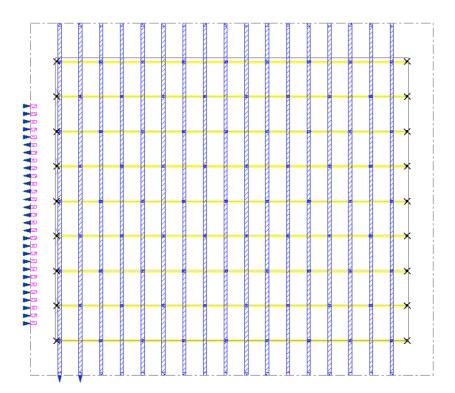
After that, using proper settings in pin editor as we discussed before, the figure will look like:



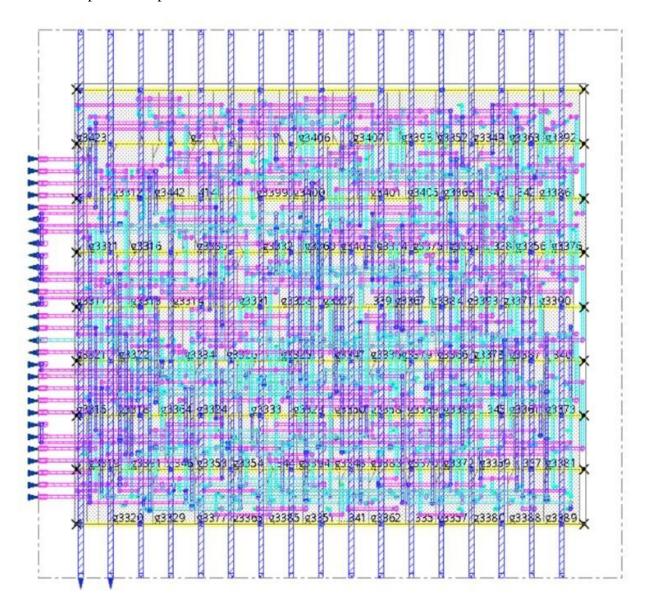
After creating the power mesh using proper settings:



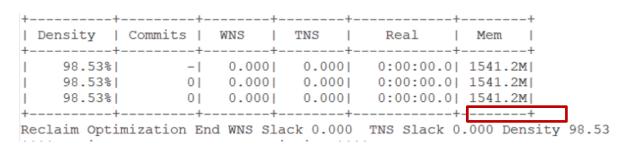
After adding M1 layer rail in the design we got:



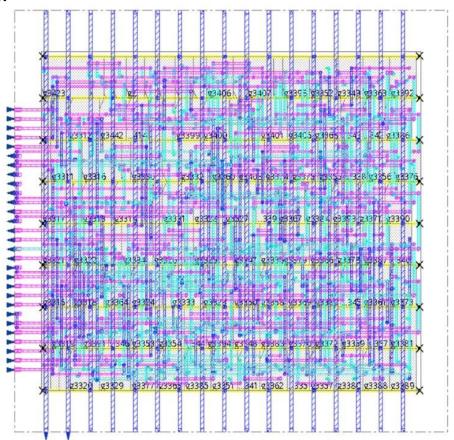
Then after placement process:



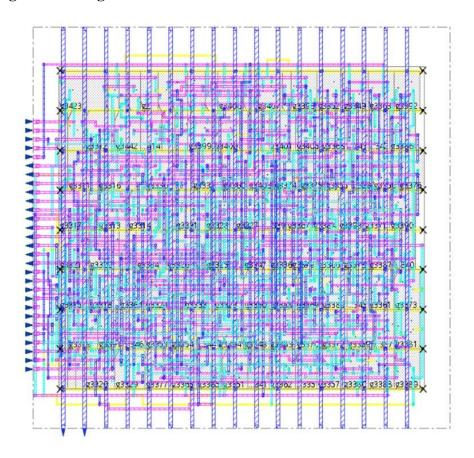
Density Data:



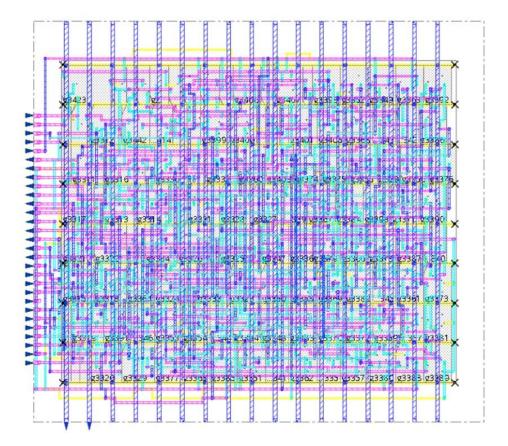
After CTS:



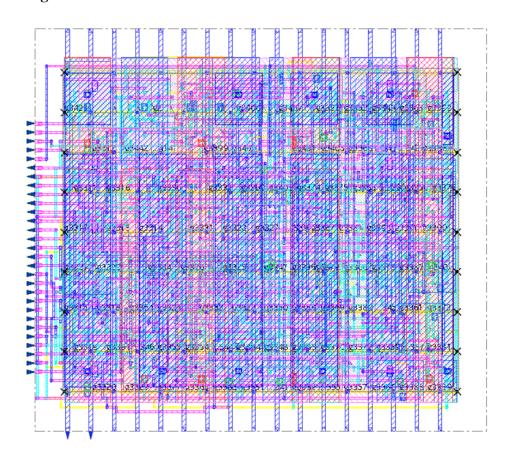
Then using nanorouting:



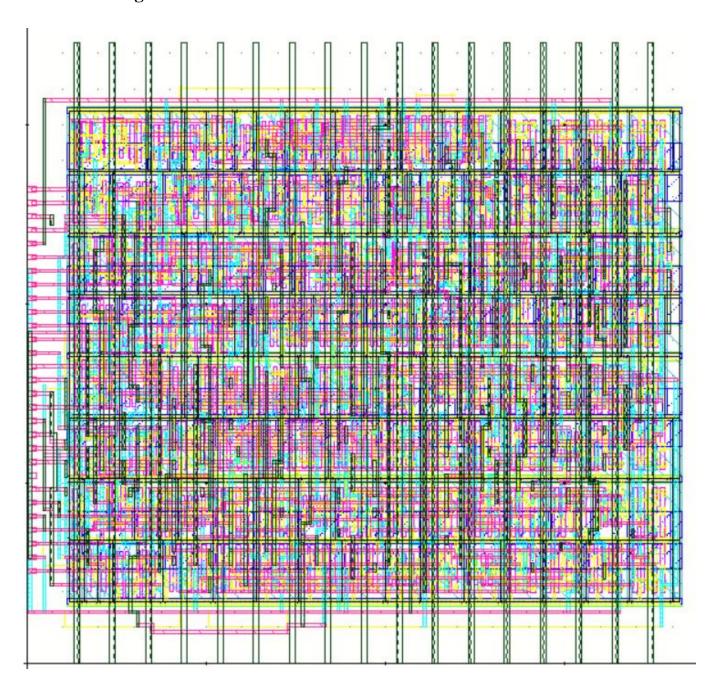
After post route timing and SI optimization, we got:



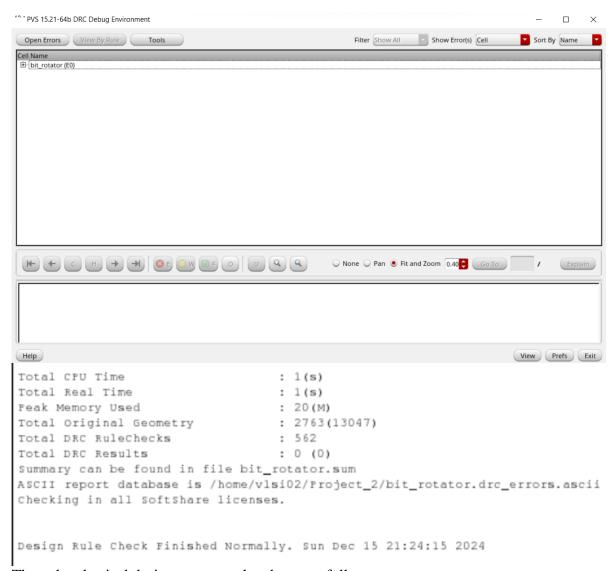
After adding metal fill:



7.1 Final design:



7.2 DRC result:



Thus, the physical design was completed successfully.

7.3 Layers with different colors that are used:



8 Conclusion:

In this project, we successfully implemented the concepts of RTL coding, directed and layered testbench with coverage, optimization of synthesis and physical design. We understood the various parameters that influence the synthesis and physical design process. We have got a maximum chip density of 98.53% which can conclude that our design is an optimized design.

9 Links of Codes and Files:

<u>Step-1:</u> https://edaplayground.com/x/BwGa
<u>Step-2:</u> https://edaplayground.com/x/8rfp

Step-3 & Step-4: /home/vlsi02/Project directory, /home/vlsi02/Project_2 directory

10 Contribution:

1906001:

- ➤ Module Design
- > Cross-checking in directed and layered testbench
- ➤ Adding coverage block to check coverage

1906004:

- Physical design of synthesized design with Innovus
- > Optimizing design area to achieve more chip density
- > Optimizing pin planning and power mesh to achieve more chip density

1906026:

- Optimizing hold time, input delay
- > Collaborating in physical design, testbench.
- > Report Writing, Presentation making

1906031:

- Synthesis with Cadence Genus
- > Optimizing setup time, hold time, input delay, output delay, clock frequency
- > Report writing and generating the plots